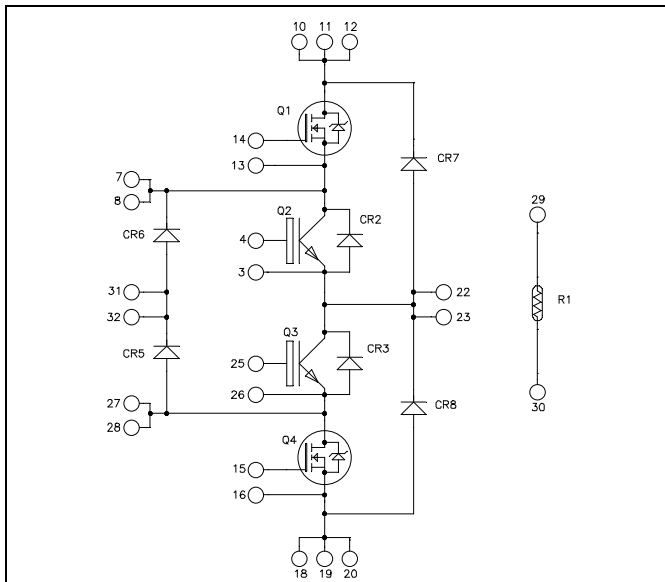


*Three level inverter
CoolMOS & Trench + Field Stop IGBT4
Power Module*

Trench & Field Stop IGBT4 Q2, Q3:
 $V_{CES} = 1200V$; $I_C = 50A$ @ $T_c = 80^\circ C$

CoolMOS™ Q1, Q4:
 $V_{DSS} = 900V$; $I_D = 23A$ @ $T_c = 80^\circ C$

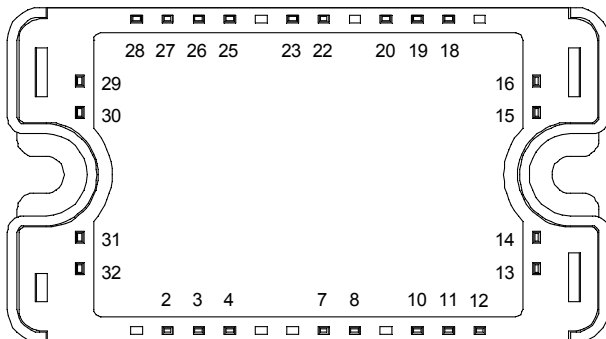


Application

- Solar converter
- Uninterruptible Power Supplies

Features

- **Q2, Q3 Trench + Field Stop IGBT 4 Technology**
 - Low voltage drop
 - Low leakage current
 - Low switching losses
- **Q1, Q4 CoolMOS™**
 - Ultra low R_{DSon}
 - Low Miller capacitance
 - Ultra low gate charge
 - Avalanche energy rated
 - Very rugged
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring



All multiple inputs and outputs must be shorted together
 Example: 10/11/12 ; 7/8 ...

Benefits

- Stable temperature behavior
- Very rugged
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive TC of V_{CESat}
- Low profile
- RoHS Compliant

All ratings @ $T_j = 25^\circ C$ unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.
 See application note APT0502 on www.microsemi.com

Q1 & Q4 Absolute maximum ratings

<i>Symbol</i>	<i>Parameter</i>	<i>Max ratings</i>	<i>Unit</i>
V _{DSS}	Drain - Source Breakdown Voltage	900	V
I _D	Continuous Drain Current	T _c = 25°C	30
		T _c = 80°C	23
I _{DM}	Pulsed Drain current	75	A
V _{GS}	Gate - Source Voltage	±20	V
R _{DSon}	Drain - Source ON Resistance	120	mΩ
P _D	Maximum Power Dissipation	T _c = 25°C	250
I _{AR}	Avalanche current (repetitive and non repetitive)	8.8	A
E _{AR}	Repetitive Avalanche Energy	2.9	mJ
E _{AS}	Single Pulse Avalanche Energy	1940	

Q1 & Q4 Electrical Characteristics

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} = 0V, V _{DS} = 900V	T _j = 25°C		100	μA
		V _{GS} = 0V, V _{DS} = 900V	T _j = 125°C		500	
R _{DS(on)}	Drain – Source on Resistance	V _{GS} = 10V, I _D = 26A		100	120	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{GS} = V _{DS} , I _D = 3mA	2.5	3	3.5	V
I _{GSS}	Gate – Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0V			100	nA

Q1 & Q4 Dynamic Characteristics

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
C _{iss}	Input Capacitance	V _{GS} = 0V ; V _{DS} = 100V f = 1MHz		6800		pF
C _{oss}	Output Capacitance			330		
Q _g	Total gate Charge	V _{GS} = 10V V _{Bus} = 400V I _D = 26A		270		nC
Q _{gs}	Gate – Source Charge			32		
Q _{gd}	Gate – Drain Charge			115		
T _{d(on)}	Turn-on Delay Time	Inductive Switching (125°C) V _{GS} = 10V V _{Bus} = 400V I _D = 26A R _G = 7.5Ω		70		ns
T _r	Rise Time			20		
T _{d(off)}	Turn-off Delay Time			400		
T _f	Fall Time			25		
R _{thJC}	Junction to Case Thermal resistance				0.5	°C/W

Q2 & Q3 Absolute maximum ratings

<i>Symbol</i>	<i>Parameter</i>	<i>Max ratings</i>	<i>Unit</i>
V _{CES}	Collector - Emitter Breakdown Voltage	1200	V
I _C	Continuous Collector Current	T _C = 25°C	80
		T _C = 80°C	60
I _{CM}	Pulsed Collector Current	T _C = 25°C	100
V _{GE}	Gate – Emitter Voltage	±20	V
P _D	Maximum Power Dissipation	T _C = 25°C	280
RBSOA	Reverse Bias Safe Operating Area	T _j = 150°C	100A @ 1100V

Q2 & Q3 Electrical Characteristics

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
I_{CES}	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} = 1200V$			1	mA
$V_{CE(sat)}$	Collector Emitter saturation Voltage	$V_{GE} = 15V$ $I_C = 50A$	$T_j = 25^\circ C$	1.8	2.2	V
			$T_j = 150^\circ C$	2.2		
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 1.6mA$	5.0	5.8	6.5	V
I_{GES}	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE} = 0V$			400	nA

Q2 & Q3 Dynamic Characteristics

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
C_{ies}	Input Capacitance	$V_{GE} = 0V$		2770		pF
C_{oes}	Output Capacitance	$V_{CE} = 25V$		205		
C_{res}	Reverse Transfer Capacitance	$f = 1MHz$		160		
Q_G	Gate charge	$V_{GE} = \pm 15V ; V_{CE} = 600V$ $I_C = 50A$		0.38		μC
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching ($25^\circ C$) $V_{GE} = \pm 15V$ $V_{CE} = 600V$ $I_C = 50A$ $R_G = 8.2\Omega$		50		ns
T_r	Rise Time			27		
$T_{d(off)}$	Turn-off Delay Time			270		
T_f	Fall Time			70		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switching ($150^\circ C$) $V_{GE} = \pm 15V$ $V_{CE} = 600V$ $I_C = 50A$ $R_G = 8.2\Omega$		50		ns
T_r	Rise Time			30		
$T_{d(off)}$	Turn-off Delay Time			290		
T_f	Fall Time			80		
E_{on}	Turn-on Switching Energy	$V_{GE} = \pm 15V$ $V_{CE} = 600V$ $I_C = 50A$	$T_j = 25^\circ C$	3.8		mJ
			$T_j = 150^\circ C$	5.5		
E_{off}	Turn-off Switching Energy	$R_G = 8.2\Omega$	$T_j = 25^\circ C$	2.5		mJ
			$T_j = 150^\circ C$	4.5		
I_{sc}	Short Circuit data	$V_{GE} \leq 15V ; V_{Bus} = 900V$ $t_p \leq 10\mu s ; T_j = 150^\circ C$		200		A
R_{thJC}	Junction to Case Thermal Resistance				0.53	$^\circ C/W$

CR5 & CR6 diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V _{RRM}	Maximum Peak Repetitive Reverse Voltage			1000			V
I _{RM}	Maximum Reverse Leakage Current	V _R =1000V	T _j = 25°C			100	μA
			T _j = 125°C			500	
I _F	DC Forward Current	T _c = 80°C			40		A
V _F	Diode Forward Voltage	I _F = 40A			2.5	3	V
		I _F = 80A			3.1		
		I _F = 40A	T _j = 125°C		2		
t _{rr}	Reverse Recovery Time	I _F = 40A V _R = 667V di/dt = 200A/μs	T _j = 25°C		250		ns
			T _j = 125°C		315		
Q _{rr}	Reverse Recovery Charge				415		nC
					1650		
E _{rr}	Reverse Recovery Energy	I _F = 40A V _R = 667V di/dt = 1000A/μs	T _j = 125°C		1.3		mJ
R _{thJC}	Junction to Case Thermal Resistance					1.2	°C/W

CR2, CR3, CR7 & CR8 diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
V _{RRM}	Maximum Peak Repetitive Reverse Voltage			1200			V
I _{RM}	Maximum Reverse Leakage Current	V _R =1200V	T _j = 25°C			100	μA
			T _j = 125°C			500	
I _F	DC Forward Current	T _c = 80°C			40		A
V _F	Diode Forward Voltage	I _F = 30A			2.6	3.1	V
		I _F = 60A			3.2		
		I _F = 30A	T _j = 125°C		1.8		
t _{rr}	Reverse Recovery Time	I _F = 30A V _R = 800V di/dt = 200A/μs	T _j = 25°C		300		ns
			T _j = 125°C		380		
Q _{rr}	Reverse Recovery Charge				360		nC
					1700		
E _{rr}	Reverse Recovery Energy	I _F = 30A V _R = 800V di/dt = 1000A/μs	T _j = 125°C		1.6		mJ
R _{thJC}	Junction to Case Thermal Resistance					1.2	°C/W

Temperature sensor NTC (see application note APT0406 on www.microsemi.com for more information).

Symbol	Characteristic	Min	Typ	Max	Unit
R ₂₅	Resistance @ 25°C		50		kΩ
ΔR ₂₅ /R ₂₅			5		%
B _{25/85}	T ₂₅ = 298.15 K		3952		K
ΔB/B	T _C = 100°C		4		%

$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$

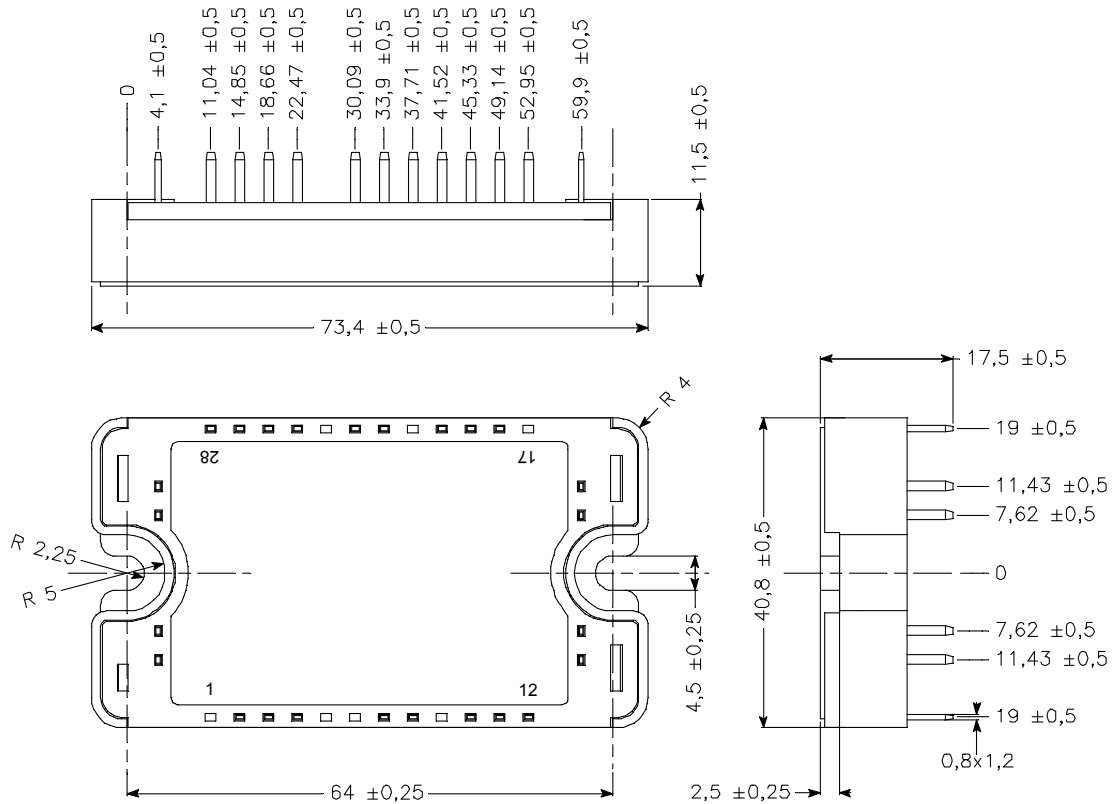
T: Thermistor temperature
 R_T: Thermistor value at T

Thermal and package characteristics

Symbol	Characteristic	Min	Typ	Max	Unit	
V_{ISOL}	RMS Isolation Voltage, any terminal to case $t=1$ min, $I_{isol}<1$ mA, 50/60Hz	2500			V	
T_J	Operating junction temperature range	-40		175*	°C	
T_{STG}	Storage Temperature Range	-40		125		
T_C	Operating Case Temperature	-40		100		
Torque	Mounting torque	To heatsink	M4	2.5	4.7	N.m
Wt	Package Weight				110	g

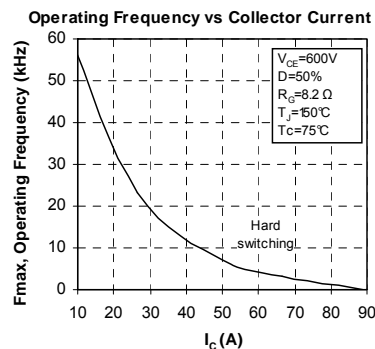
* $T_{jmax} = 150^{\circ}\text{C}$ for Q1 & Q4

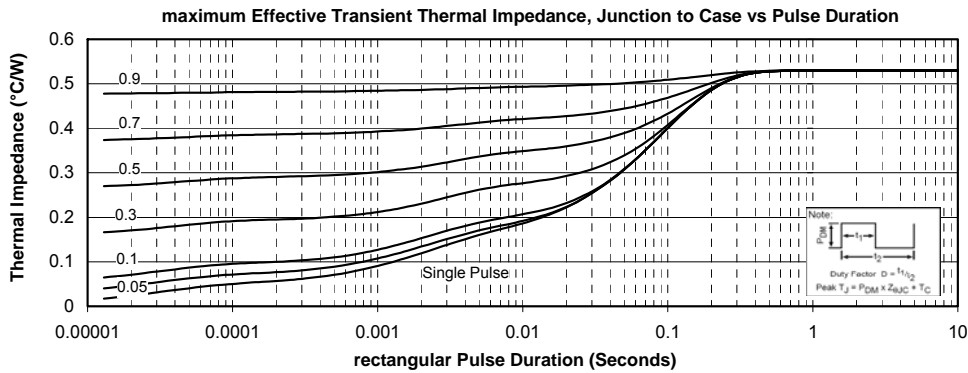
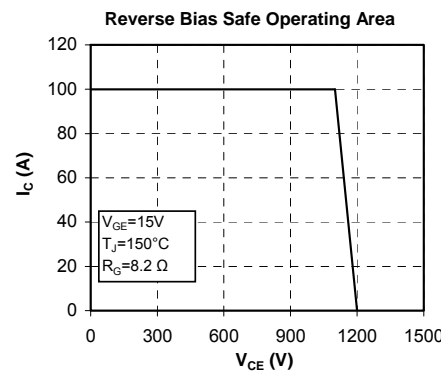
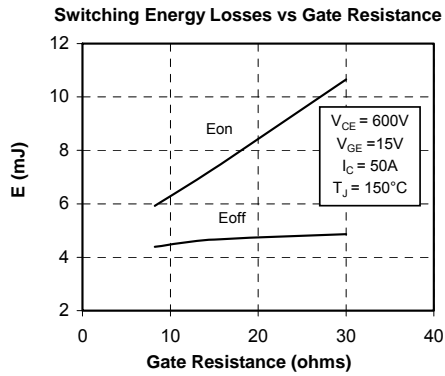
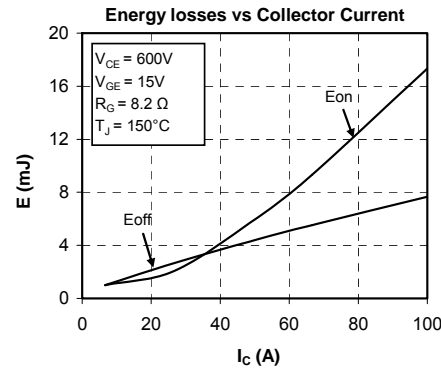
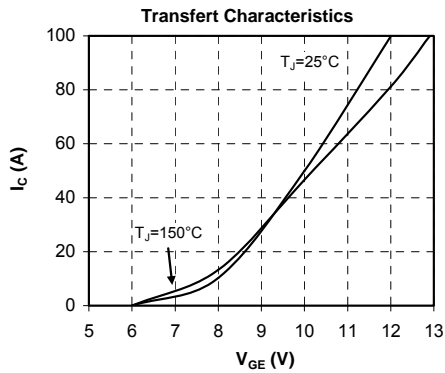
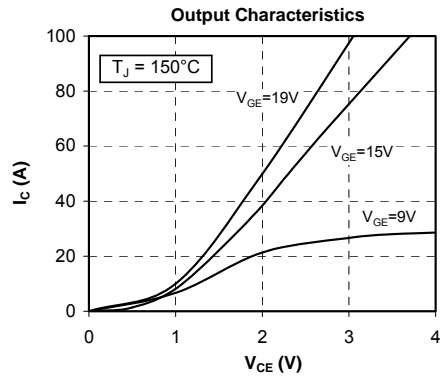
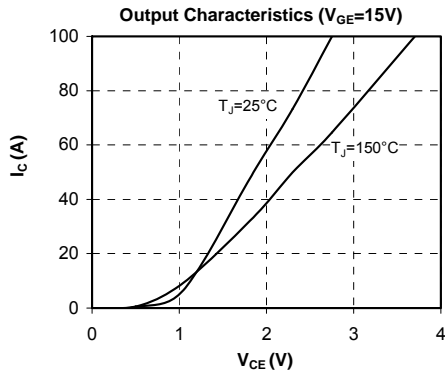
SP3 Package outline (dimensions in mm)



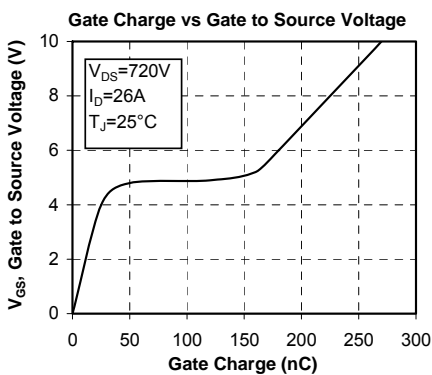
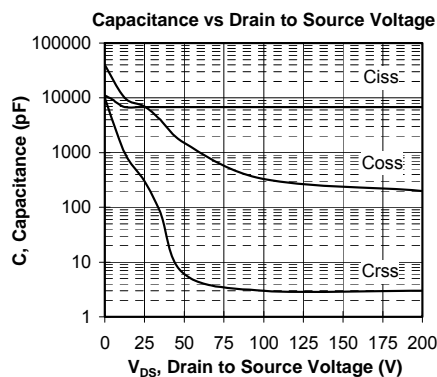
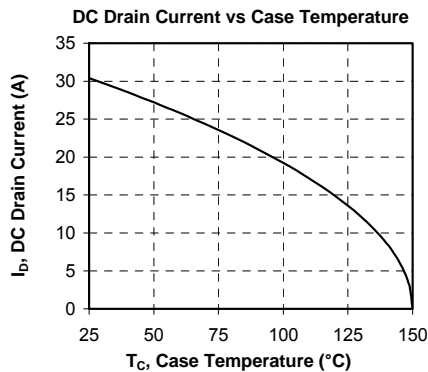
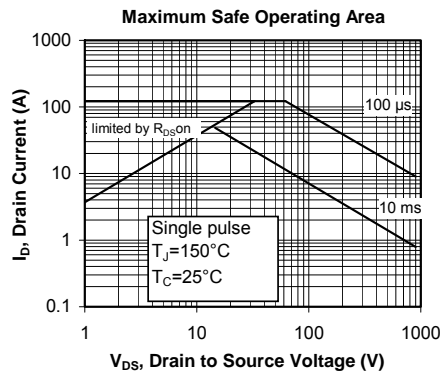
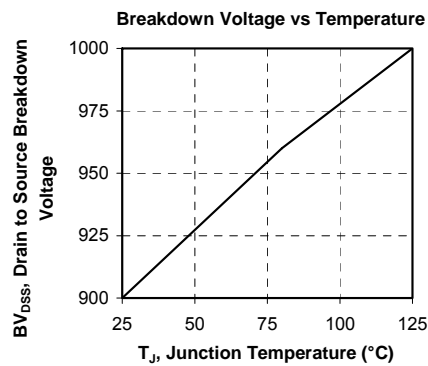
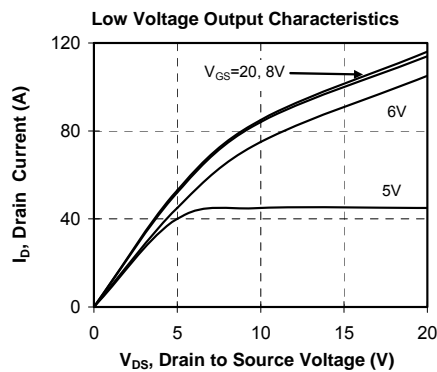
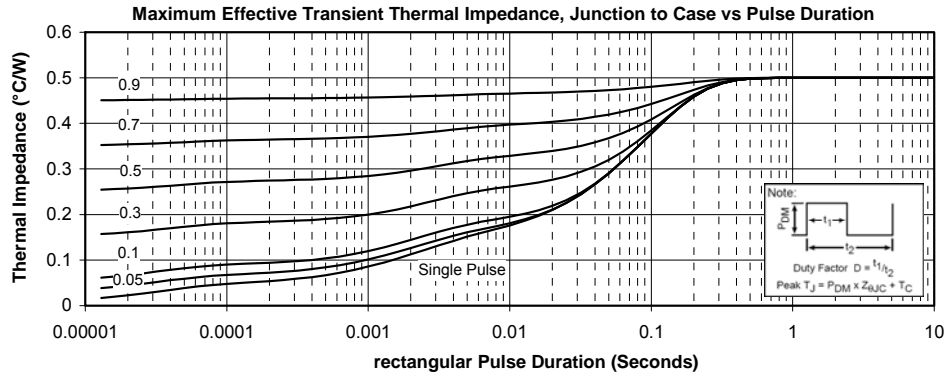
See application note 1901 - Mounting Instructions for SP3 Power Modules on www.microsemi.com

Q2 & Q3 Typical performance curve

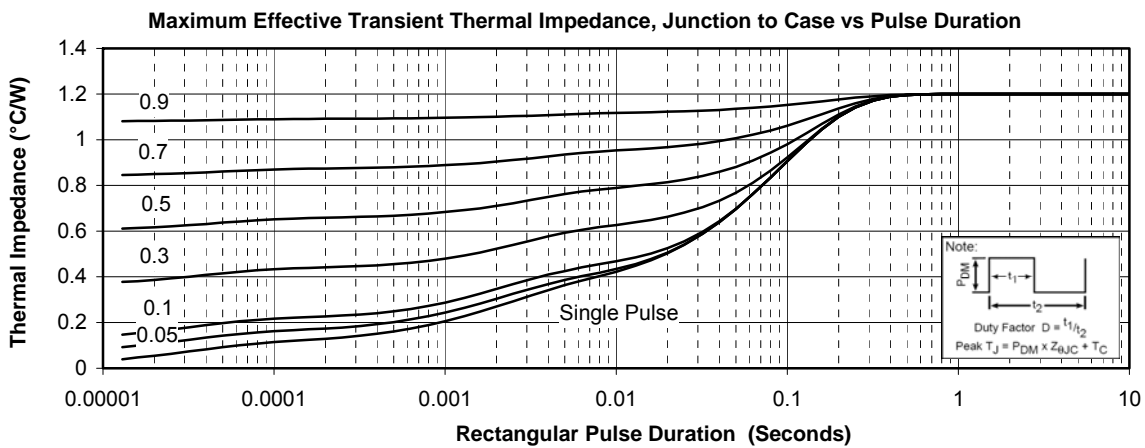
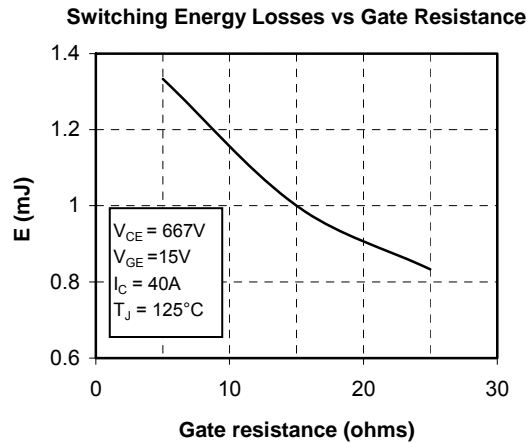
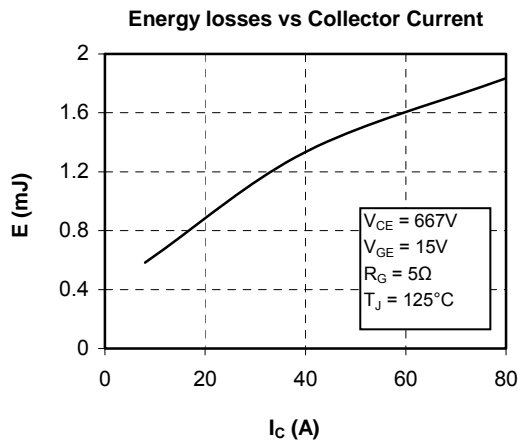
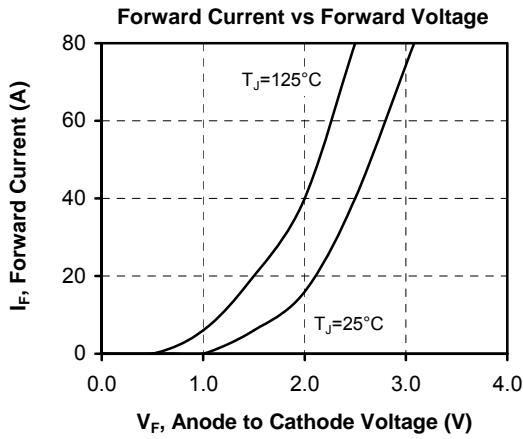




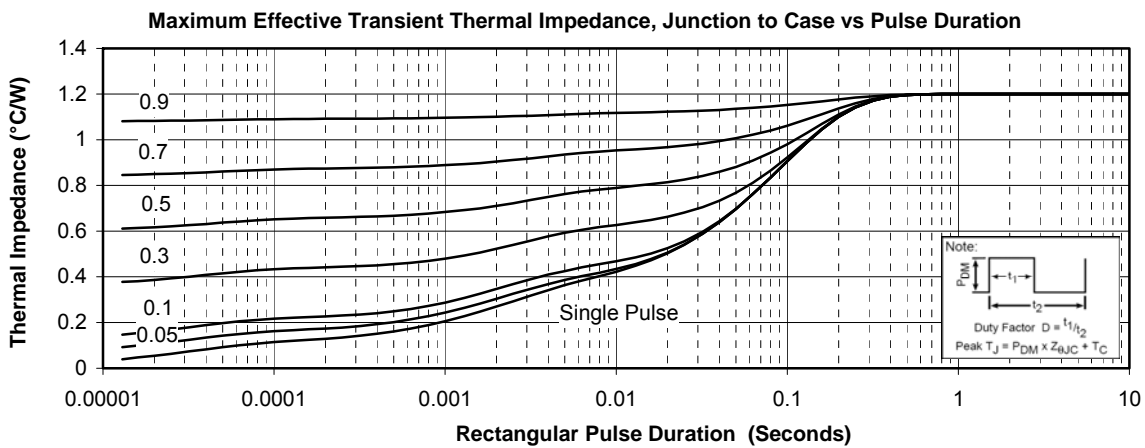
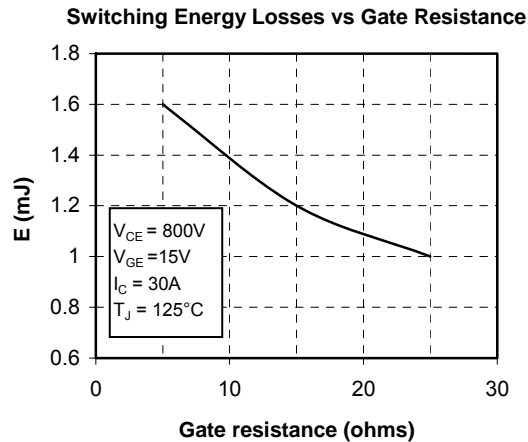
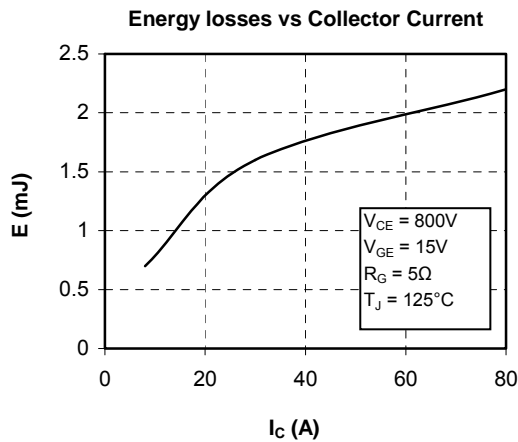
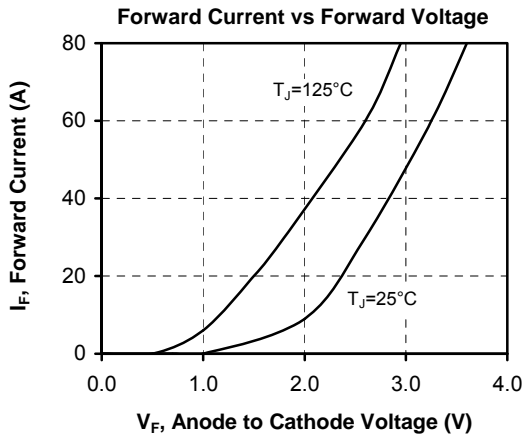
Q1 & Q4 Typical performance curve



CR5 & CR6 Typical performance curve



CR2, CR3, CR7 & CR8 Typical performance curve



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Microsemi's products are covered by one or more of U.S. patents 4,895,810 5,045,903 5,089,434 5,182,234 5,019,522 5,262,336 6,503,786 5,256,583 4,748,103 5,283,202 5,231,474 5,434,095 5,528,058 6,939,743 7,352,045 5,283,201 5,801,417 5,648,283 7,196,634 6,664,594 7,157,886 6,939,743 7,342,262 and foreign patents. U.S and Foreign patents pending. All Rights Reserved.